

Supporting Information

Delta-temperatural electronic transportations achieved in metastable perovskites rare-earth nickelates thin films

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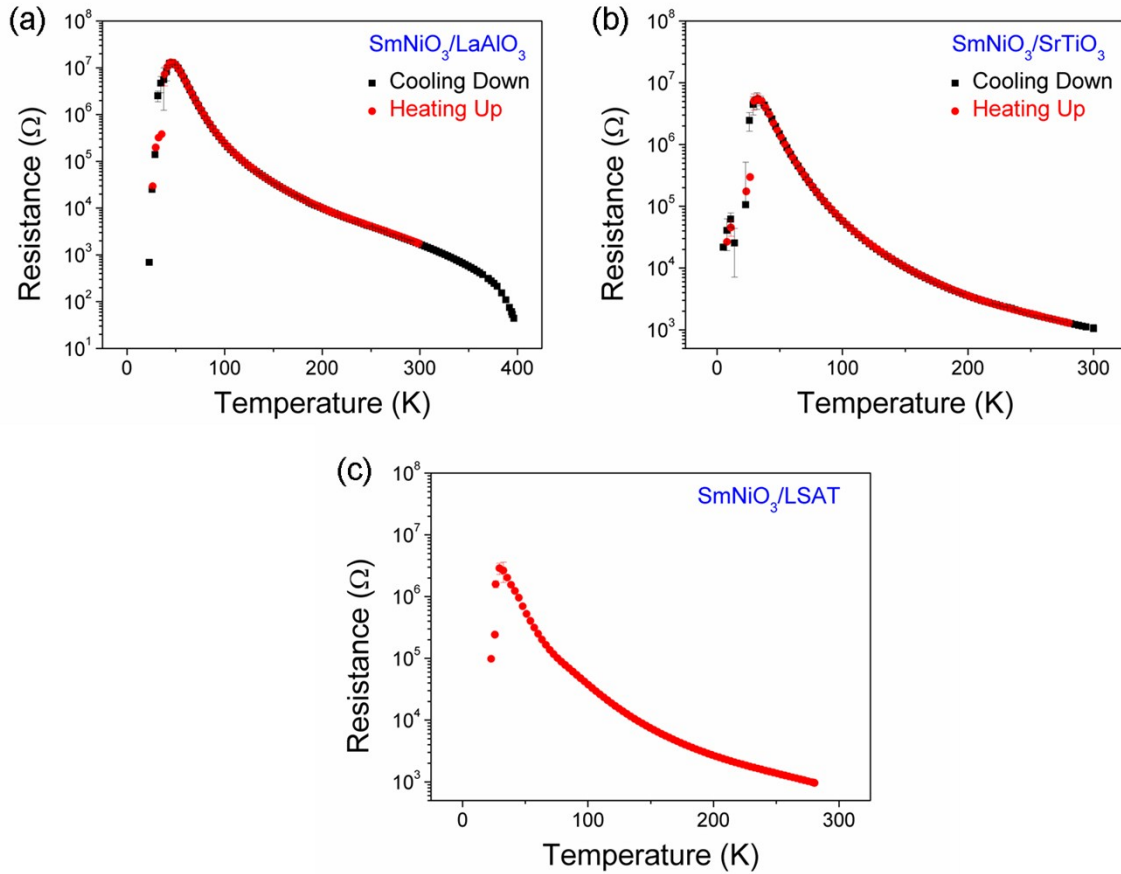


Figure S1. The resistance of SmNiO₃ (SNO) on (a) LaAlO₃ (LAO), (b) SrTiO₃ (STO) and (c) (LaAlO₃)_{0.3}(Sr₂AlTaO₆)_{0.7} (LSAT) substrates with a (001) orientation measured as a function of temperature.

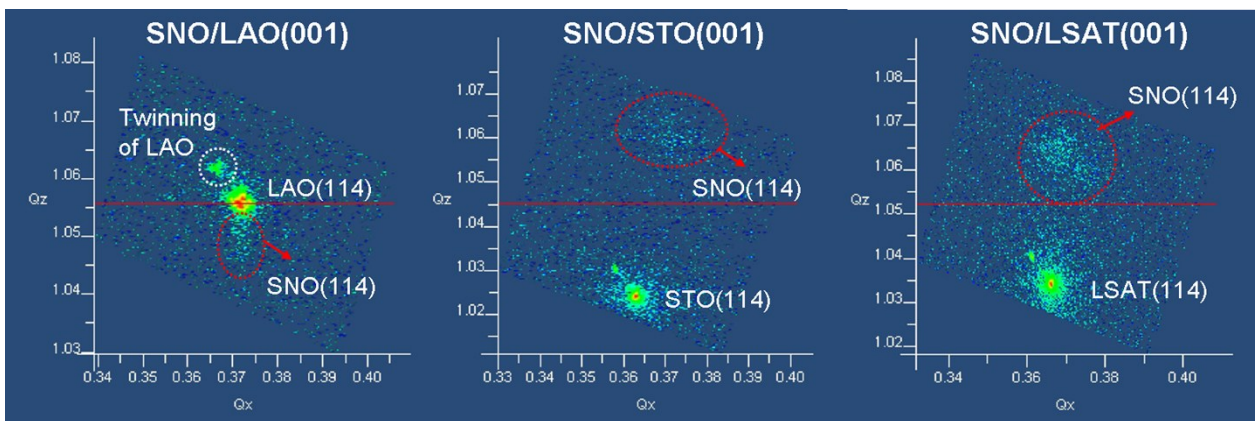


Figure S2. The X-ray reciprocal space mapping of SmNiO₃ (SNO) grown on single crystalline perovskite structured substrates, such as LaAlO₃ (LAO), SrTiO₃ (STO) and (LaAlO₃)_{0.3}(Sr₂AlTaO₆)_{0.7} (LSAT) with (001) orientation via the chemical approach reported previously. The reciprocal vector of (114) is used to probe the diffraction patterns from both the thin film and the substrate.

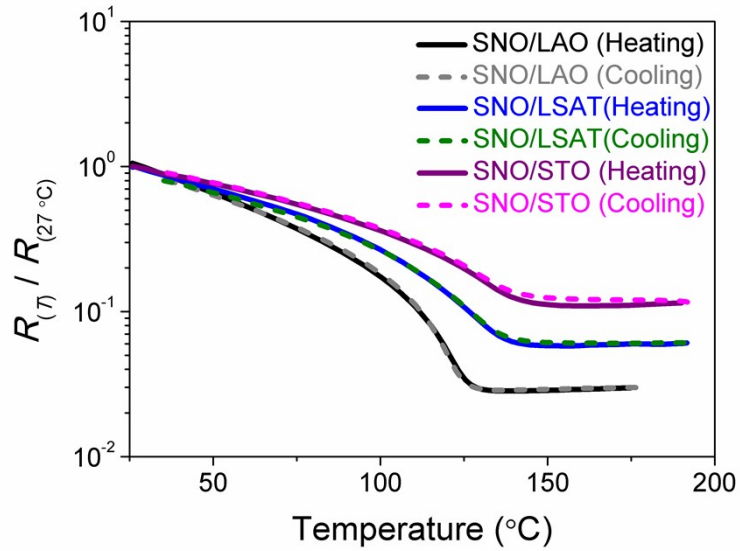


Figure S3. The temperature dependence in resistivity for $\text{SmNiO}_3/\text{LaAlO}_3$, $\text{SmNiO}_3/\text{SrTiO}_3$, and $\text{SmNiO}_3/(\text{La,Sr})(\text{Al,Ta})\text{O}_3$, measured via heating up (solid lines) and cooling down (dash lines). A lower metal to insulator transition temperature (T_{MIT}) is observed for the bi-axial distorted $\text{SmNiO}_3/(\text{La,Sr})(\text{Al,Ta})\text{O}_3$, compared to the partially tensile strain relaxed $\text{SmNiO}_3/\text{SrTiO}_3$, and $\text{SmNiO}_3/(\text{La,Sr})(\text{Al,Ta})\text{O}_3$. These observations are in agreement to the previous reports on strain distorted SmNiO_3 .

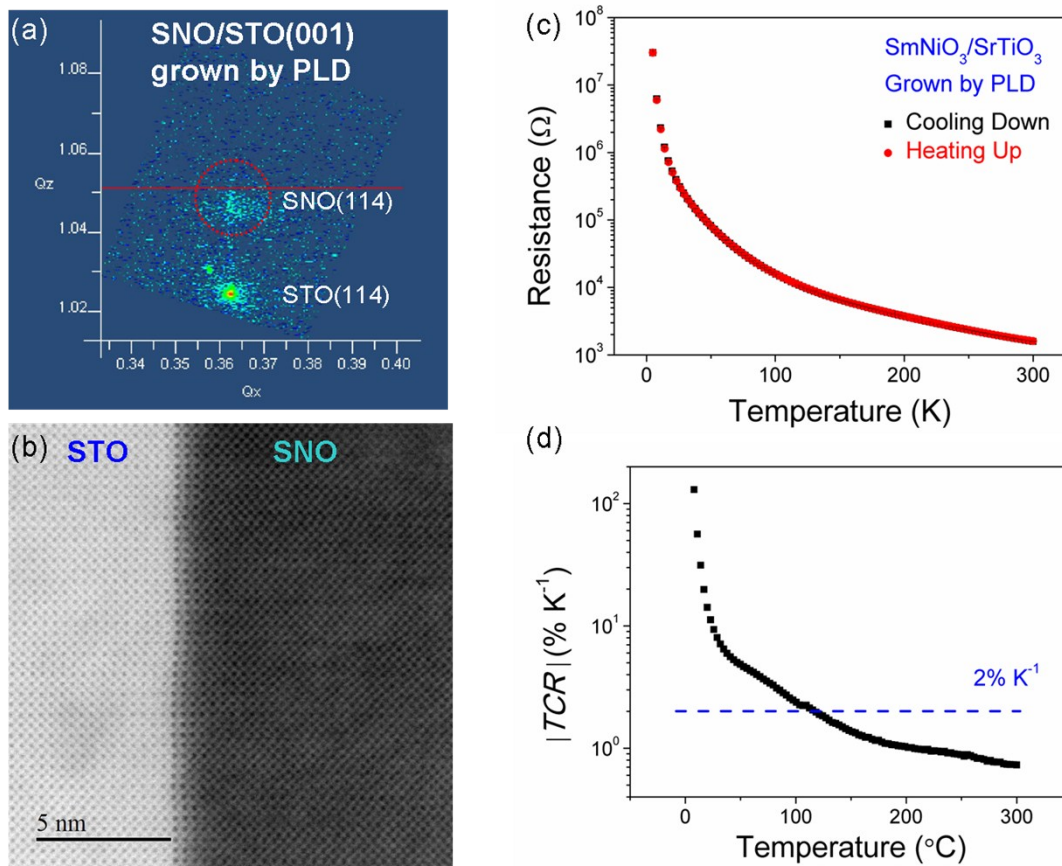


Figure S4. (a) The X-ray reciprocal space mapping of SmNiO₃ (SNO) grown on single crystalline SrTiO₃ (STO) with (001) orientation via pulsed laser deposition. The reciprocal vector of (114) is used to probe the diffraction patterns from both the thin film and the substrate. (b) The interfacial morphology of as-grown SmNiO₃ /SrTiO₃ from the high-angle annular dark-field (HAADF) images. (c) Temperature dependence of the resistivity and (d) Temperature coefficients of resistance (TCR) for as-grown SmNiO₃/SrTiO₃.

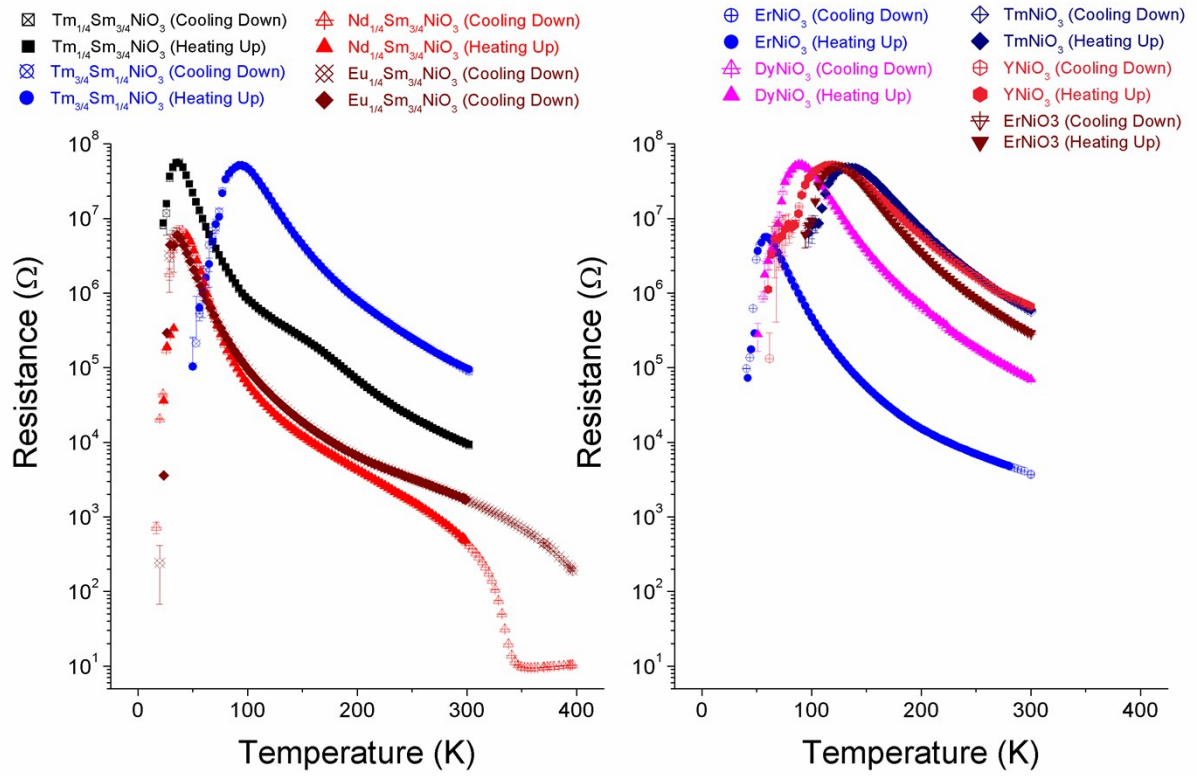


Figure S5. The resistance of $ReNiO_3$ grown on the $LaAlO_3$ (001) substrate with single and multiple rare earth compositions measured as a function of temperature.

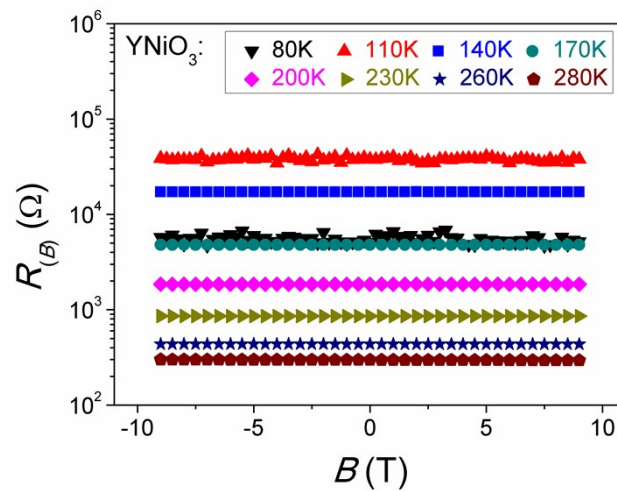


Figure S6. Resistance of $YNiO_3$ measured as a function of the imparted external magnetic fields (B) at various temperatures.

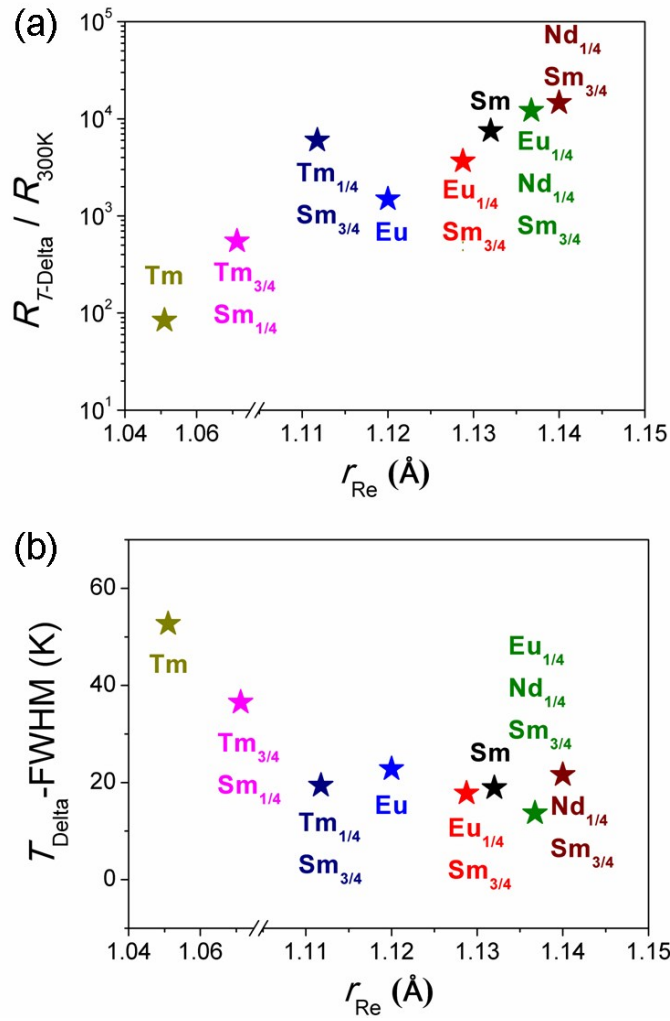


Figure S7. (a) The maximum resistivity at $T_{\text{R-MIT}}$ compared to the one at 300 K, and (b) the full widths half maximum of its resultant delta-shaped temperature dependence in resistivity ($T_{\text{Delta-FWHM}}$) summarized from the R - T of multiple rare-earth composition perovskite nickelates shown in Figure 4a.